

<b>Notice of References Cited</b>	Application/Control No. 10/533,730		Applicant(s)/Patent Under Reexamination LAMBERT ET AL.	
	Examiner Kezhen Shen		Art Unit 2627	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,972,401 A	11-1990	Carasso et al.	369/47.49
*	B	US-5,418,764 A	05-1995	Roth et al.	369/30.04
*	C	US-5,608,717 A	03-1997	Ito et al.	369/275.3
*	D	US-5,941,649 A	08-1999	Hansel et al.	400/703
*	E	US-6,325,950 B1	12-2001	Hosokawa et al.	264/1.33
*	F	US-2002/0012315 A1	01-2002	Iida et al.	369/275.1
*	G	US-6,388,962 B1	05-2002	Mons, Johannes J.	369/44.26
*	H	US-2002/0105888 A1	08-2002	Levich et al.	369/94
*	I	US-2004/0017746 A1	01-2004	Takeda et al.	369/47.35
*	J	US-2004/0052202 A1	03-2004	Brolhier, Brian W.	369/273
*	K	US-7,164,633 B2	01-2007	Iida et al.	369/47.27
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.